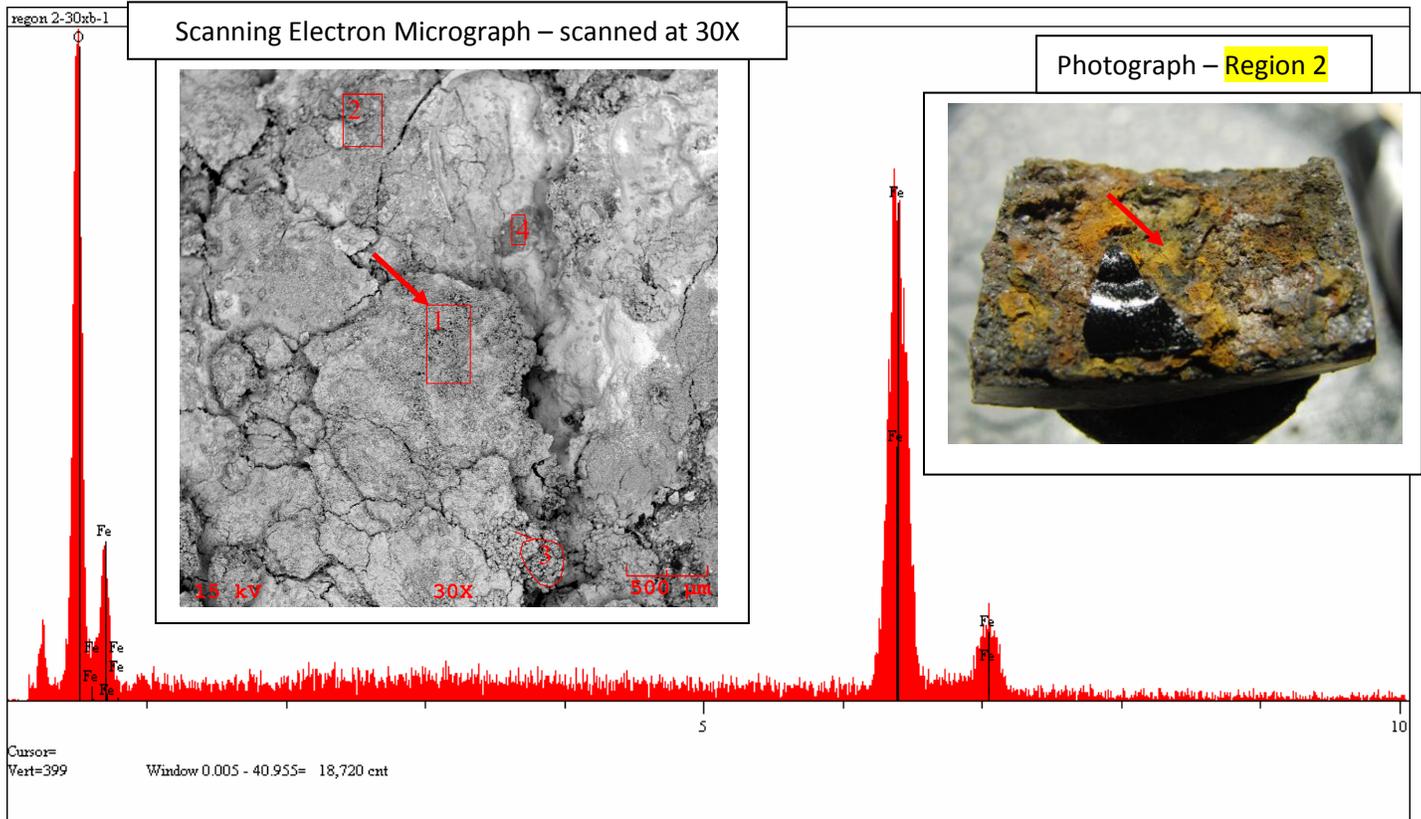
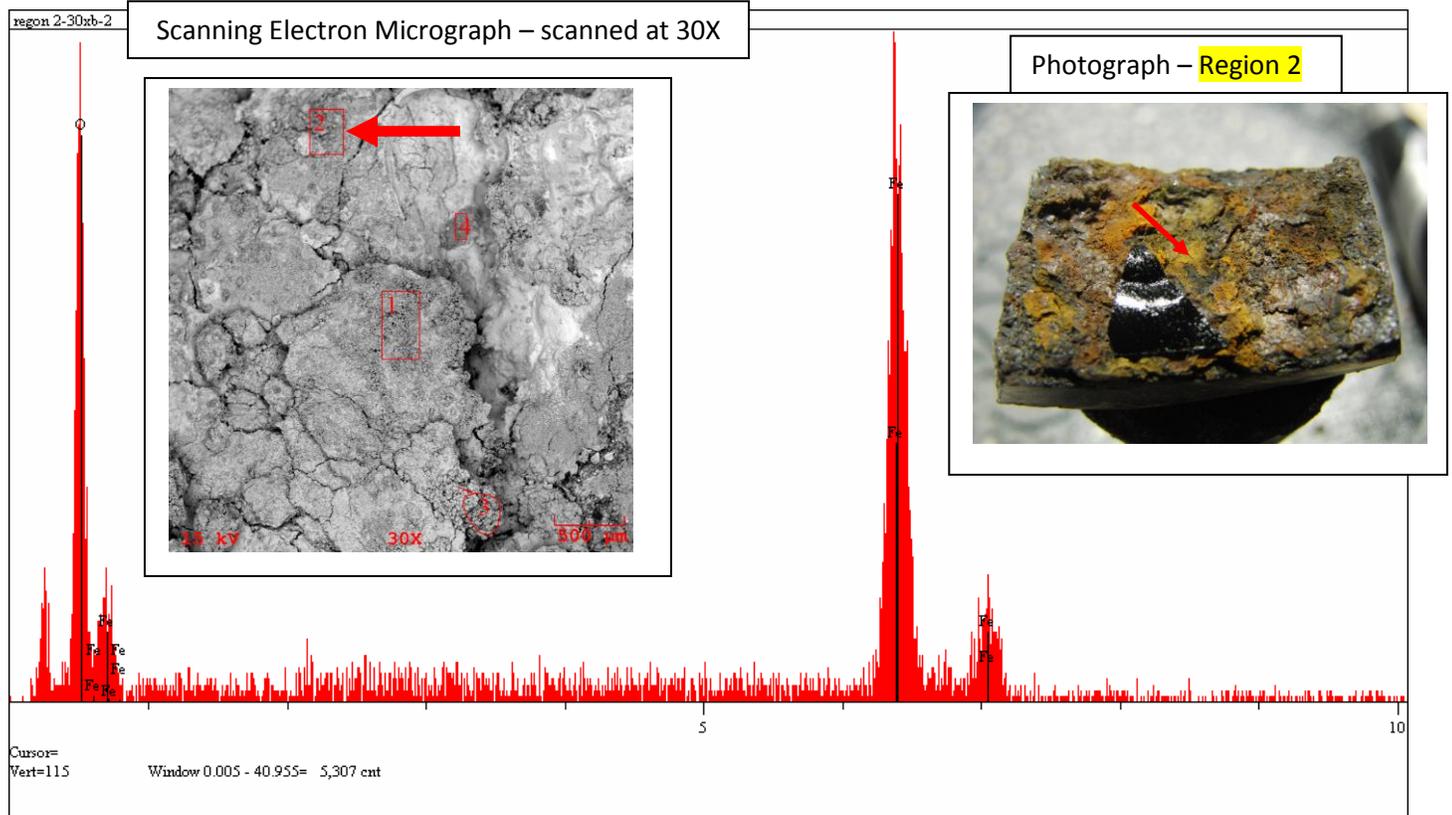




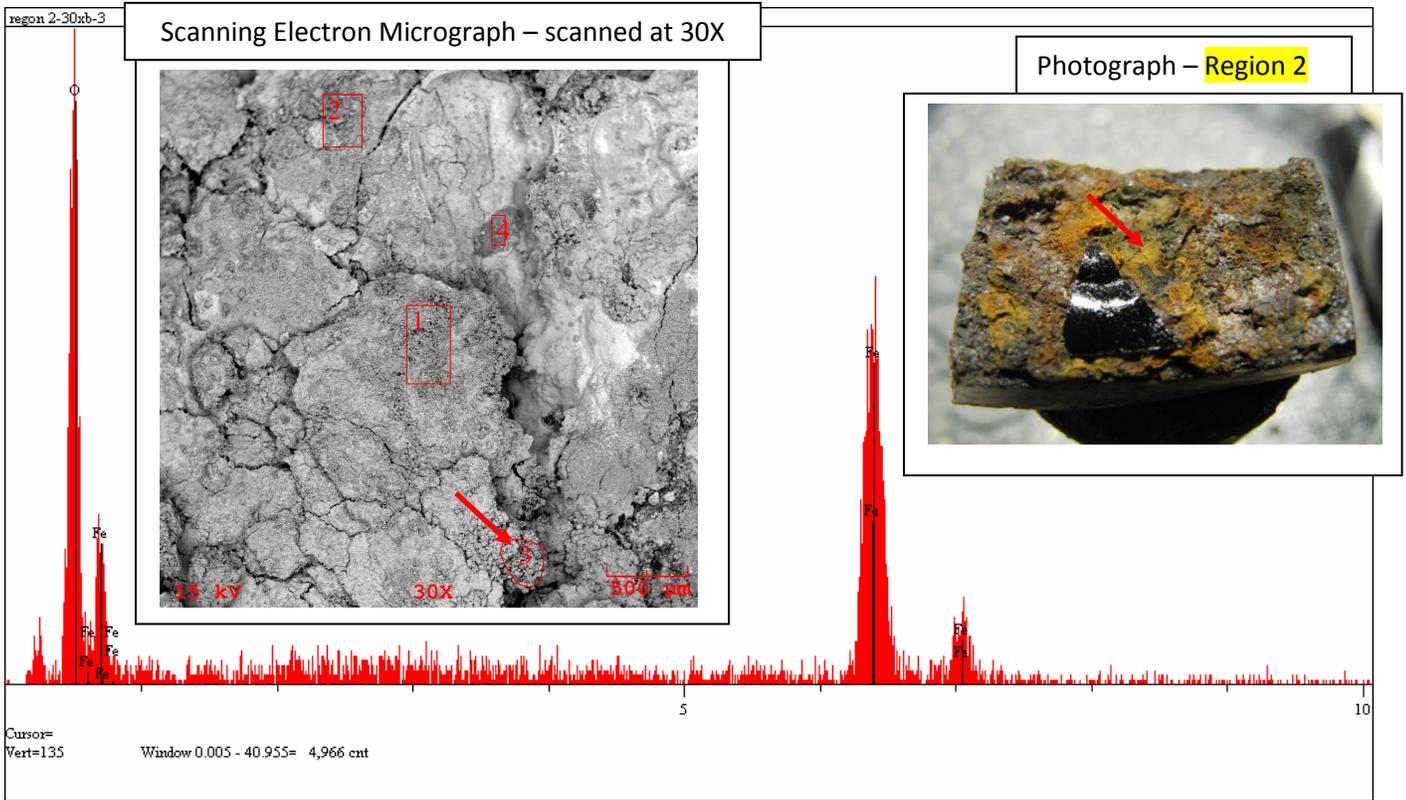
Sample 1/8 – SEM/EDS – elemental analysis – scanned at 30X – BSE detector



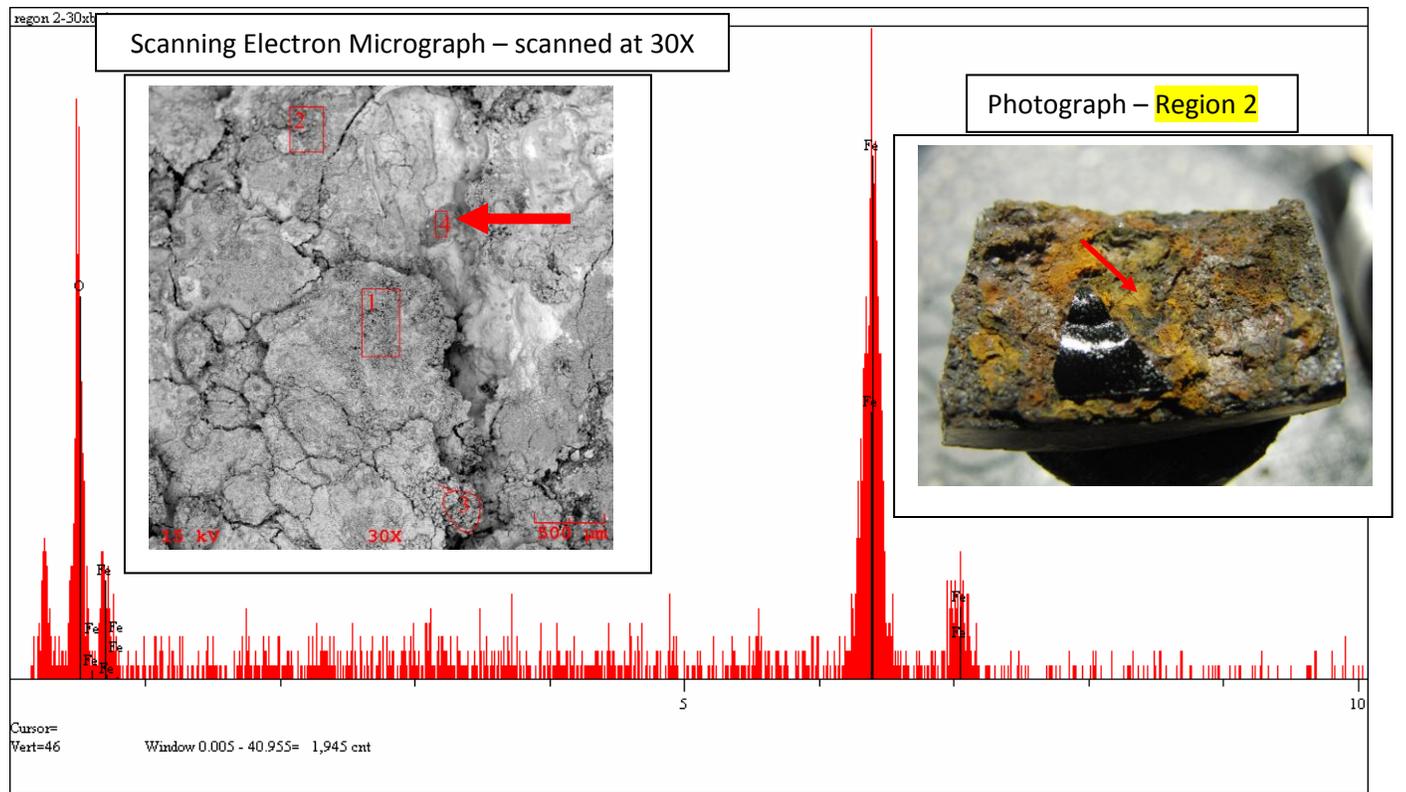
Defect region -- SEM/EDS – elemental analysis – scanned at 30X



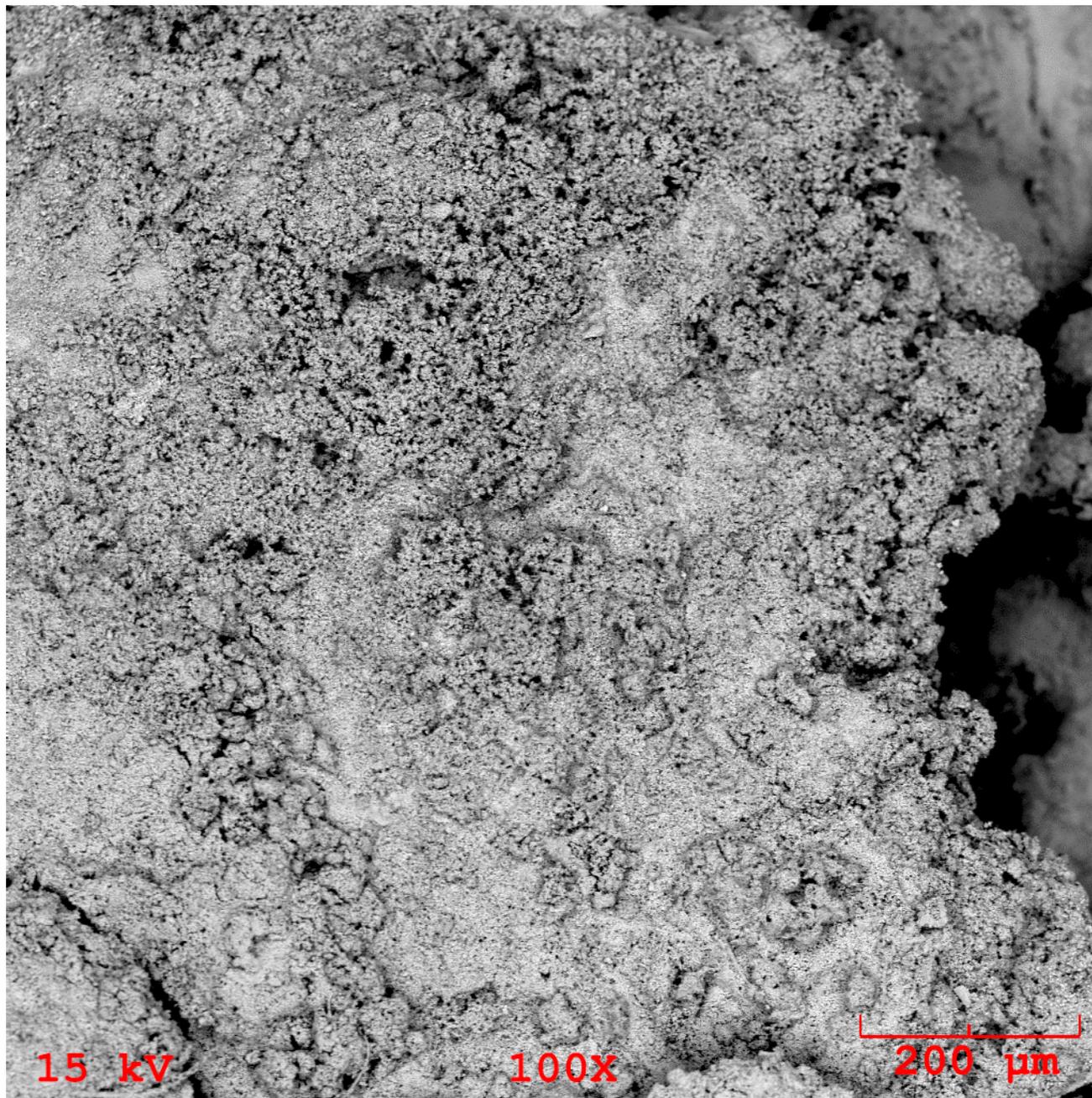
Sample 1/8 – SEM/EDS – elemental analysis – scanned at 30X – BSE detector



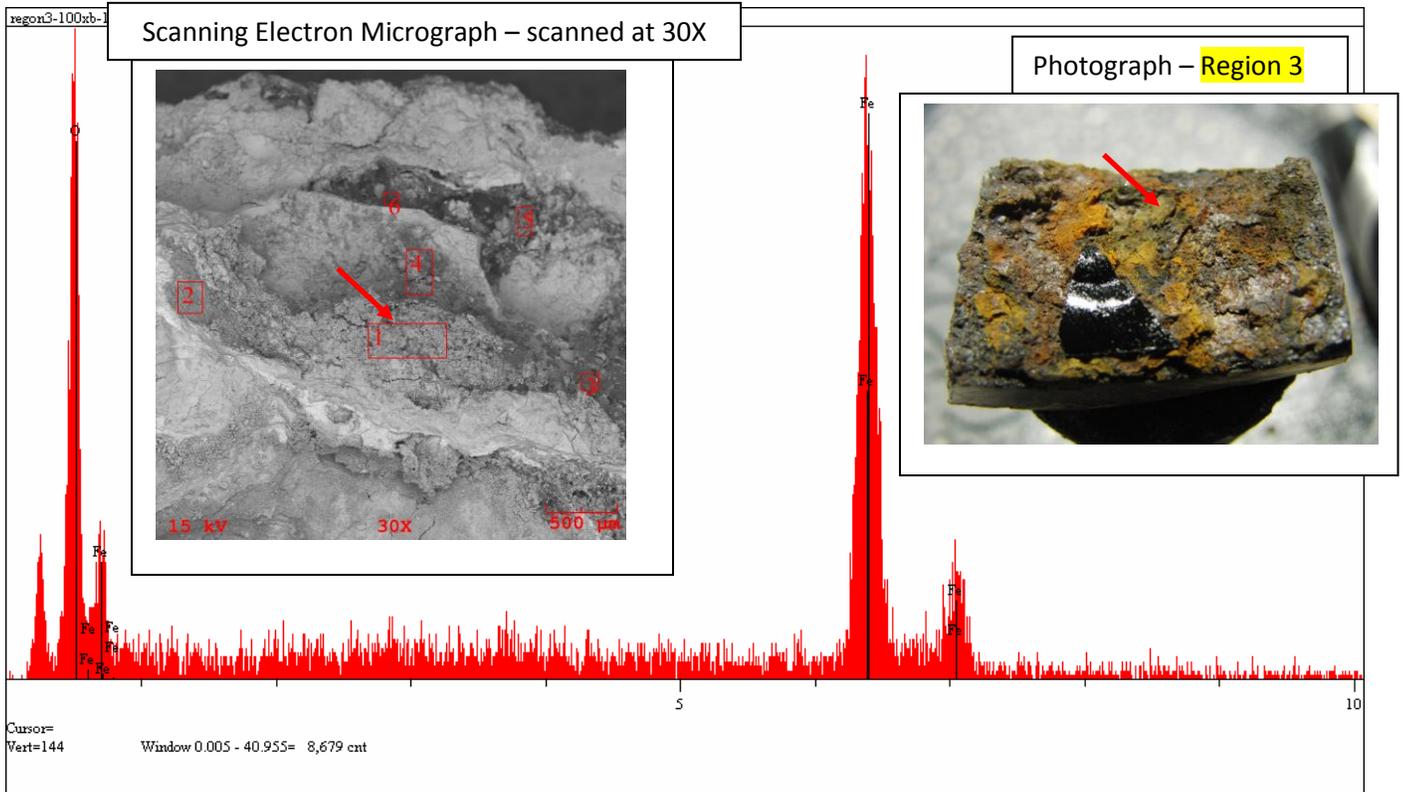
Defect region -- SEM/EDS – elemental analysis



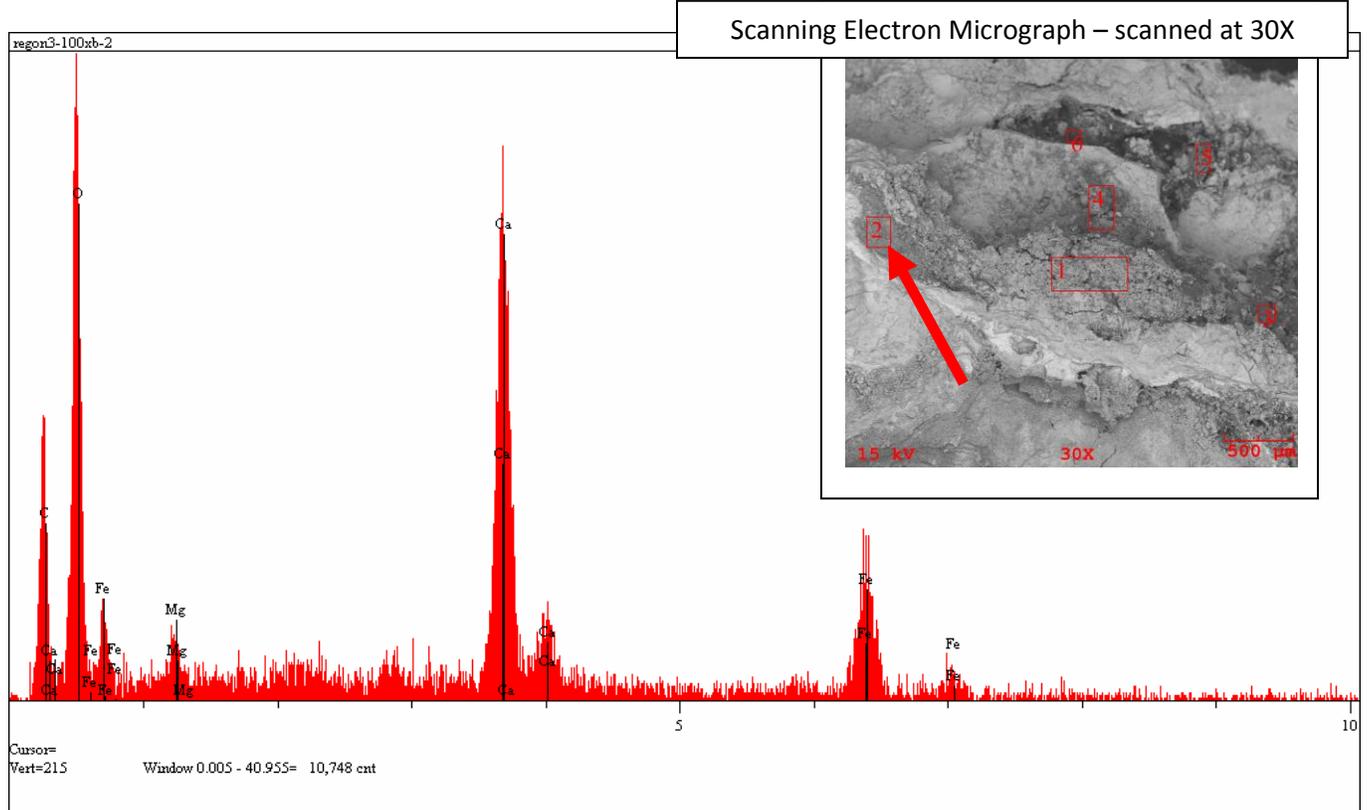
SEM Micrograph – Scanned at 100X – Region 2 from Photomicrograph



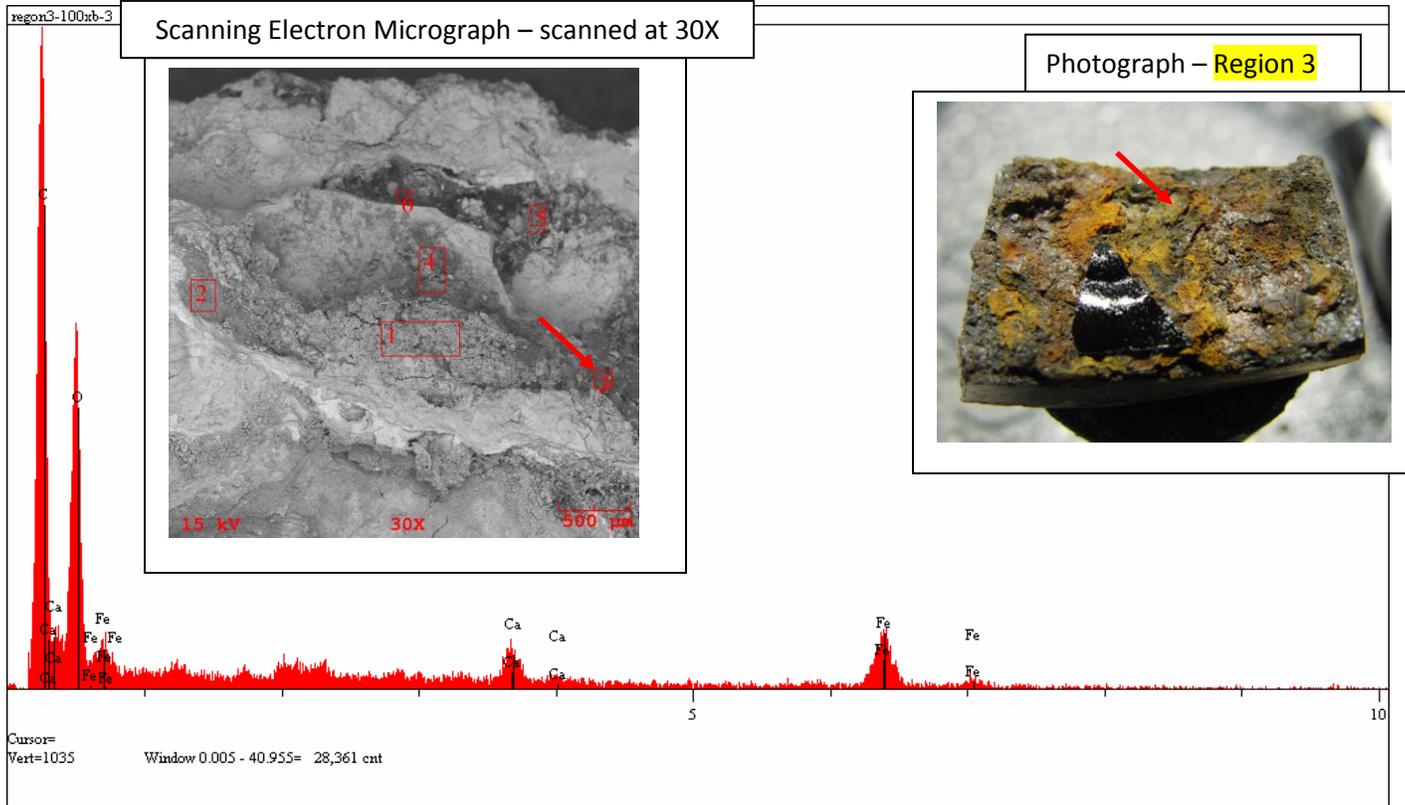
Sample 1/8 – SEM/EDS – elemental analysis – scanned at 30X – BSE detector



Defect region -- SEM/EDS – elemental analysis – scanned at 30X



Sample 1/8 – SEM/EDS – elemental analysis – scanned at 30X – BSE detector



Defect region -- SEM/EDS – elemental analysis – scanned at 30X

